

☐ Probe ☐ Scope ☐ View

pt. 16 PARTIAL USAF: CPT; PRT; DEPEND; NEW TPO

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(shielded as probe) and test(s) near(semiconductor or integrated ad circuit)

(shielded ad) probe) and test 54 near (semiconductor or integrated ad) circuit)

n	i	Document ID	Issue Date	Pages	Title	Current OR	Current Ref.	Retrieval C	Inventor	S	C	T	A
1	P	US 2904817A1 B1	1960-03-09	15	Apparatus and method for terminating probe apparatus	324/754			Foot, Bryan J. et al.	R	I	I	I
2	P	US 2304835A1 B1	1960-03-09	11	Shielded probe apparatus for probing semiconductor wafer	324/754			Foot, Bryan J. et al.	R	I	I	I
3	P	US 2905022A1 B1	1960-03-12	15	Apparatus for providing controlled impedance in an	439/620			Johanson, David A. et al.	R	I	I	I
4	P	US 2902057A1 B1	1960-03-20	53	Triaxial probe assembly	324/765			Hollman, Kenneth et al.	R	I	I	I
5	P	US 2901059A1 B1	1960-03-20	14	Test socket	324/755			Swart, Mark A. et al.	R	I	I	I
6	P	US 6727718 B1	2004-09-27	12	Probe card and probe needle for high frequency testing	324/754	324/761		Ghorif, Adnan K.	R	I	I	I
7	P	US 8700357 B2	2004-03-02	49	Triaxial probe assembly	324/762	324/765		Hollman, Kenneth et al.	R	I	I	I
8	P	US 6204280 B1	2001-03-20	13	Test socket	324/761	324/755; 324/756		Swart, Mark A. et al.	R	I	I	I
9	P	US 5367845 A	1995-10-19	13	Apparatus for providing controlled impedance in an	439/620	439/66		Johanson, David A. et al.	R	I	I	I